## Notice of References Cited Application/Control No. 09/915,554 Examiner JOHN J. LEE Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,583,866	12-1996	Vook et al.	455/67.7
*	В	US-5,844,900	12-1998	Hong et al.	370/342
*	С	US-6,359,901	03-2002	Todd et al.	370/465
*	D	US-6,940,831	09-2005	Omi et al.	370/310.1
	Ε	US-			
	F	US-			***
•	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Φ					
	σ					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	<b>&gt;</b>	
	8	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.